# XN09D58

### Silicon PNP epitaxial planar type (Tr) Silicon epitaxial planar type (SBD)

#### For DC-DC converter

#### Features

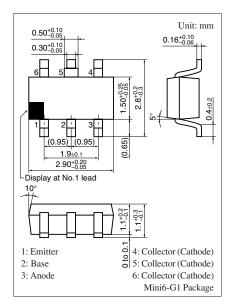
- Two elements incorporated into one package (Tr + SBD)
- Reduction of the mounting area and assembly cost by one half
- Low collector-emitter saturation voltage  $V_{CE(sat)}$

#### Basic Part Number

• XN9D57 + MA3ZD12

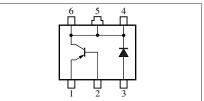
#### Absolute Maximum Ratings $T_a = 25^{\circ}C$

|         | Parameter                                | Symbol             | Rating      | Unit |  |
|---------|--|--------------------|-------------|------|--|
| Tr      | Collector-base voltage<br>(Emitter open) | V <sub>CBO</sub>   | -15         | V    |  |
|         | Collector-emitter voltage<br>(Base open) | V <sub>CEO</sub>   | -15         | V    |  |
|         | Emitter-base voltage<br>(Collector open) | V <sub>EBO</sub>   | -5          | V    |  |
|         | Collector current                        | I <sub>C</sub>     | -2.5        | А    |  |
|         | Peak collector current                   | I <sub>CP</sub>    | -10         | А    |  |
| SBD     | Reverse voltage                          | V <sub>R</sub>     | 20          | V    |  |
|         | Repetitive peak reverse voltage          | V <sub>RRM</sub>   | 25          | V    |  |
|         | Forward current (Average)                | I <sub>F(AV)</sub> | 700         | mA   |  |
|         | Non-repetitive peak                      | I <sub>FSM</sub>   | 2           | А    |  |
|         | forward surge current                    |                    |             |      |  |
| Overall | Total power dissipation *                | P <sub>T</sub>     | 600         | mW   |  |
|         | Junction temperature                     | Tj                 | 125         | °C   |  |
|         | Storage temperature                      | T <sub>stg</sub>   | -55 to +125 | °C   |  |



#### Marking Symbol: EF

#### Internal Connection



Note) \*: Measuring on ceramic substrate at 15 mm  $\times$  15 mm  $\times$  0.6 mm

Electrical Characteristics  $T_a = 25^{\circ}C \pm 3^{\circ}C$ 

#### • Tr

| Parameter                                    | Symbol               | Conditions   | Min | Тур  | Max   | Unit |
|--|----------------------|--|-----|------|-------|------|
| Collector-base voltage (Emitter open)        | V <sub>CBO</sub>     | $I_{C} = -10 \ \mu A, \ I_{E} = 0$                       | -15 |      |       | V    |
| Collector-emitter voltage (Base open)        | V <sub>CEO</sub>     | $I_{\rm C} = -1  {\rm mA},  I_{\rm B} = 0$               | -15 |      |       | V    |
| Emitter-base voltage (Collector open)        | V <sub>EBO</sub>     | $I_E = -10 \ \mu A, \ I_C = 0$                           | -5  |      |       | V    |
| Collector-base cutoff current (Emitter open) | I <sub>CBO</sub>     | $V_{CB} = -10 \text{ V}, I_E = 0$                        |     |      | - 0.1 | μΑ   |
| Forward current transfer ratio *             | h <sub>FE1</sub>     | $V_{CE} = -2 V, I_C = -100 mA$                           | 200 |      | 560   |      |
|  | h <sub>FE2</sub>     | $V_{CE} = -2 V, I_C = -2.5 A$                            | 100 |      |       |      |
| Collector-emitter saturation voltage *       | V <sub>CE(sat)</sub> | $I_{C} = -1 A, I_{B} = -10 mA$                           |     | -140 |       | mV   |
|  |                      | $I_{\rm C} = -2.5 \text{ A}, I_{\rm B} = -50 \text{ mA}$ |     | -270 | -320  |      |

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors. 2. \*: Pulse measurement

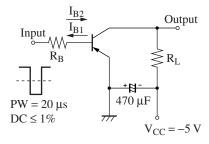
#### Electrical Characteristics (continued) $T_a = 25^{\circ}C \pm 3^{\circ}C$

• Tr (continued)

| Parameter                           | Symbol           | Conditions   | Min | Тур | Max | Unit |
|-------------------------------------|------------------|--|-----|-----|-----|------|
| Collector output capacitance        | C <sub>ob</sub>  | $V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$               |     | 40  |     | pF   |
| (Common base, input open circuited) |                  |  |     |     |     |      |
| Transition frequency                | f <sub>T</sub>   | $V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$ |     | 180 |     | MHz  |
| Turn-on time                        | t <sub>on</sub>  | Refer to the switching time measurement circuit                    |     | 35  |     | ns   |
| Storage time                        | t <sub>stg</sub> |  |     | 110 |     | ns   |
| Turn-off time                       | t <sub>off</sub> |  |     | 10  |     | ns   |

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

Switching time measurement circuit



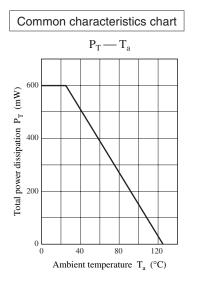
$$-20I_{B1} = 20I_{B2} = I_C = -1.5 A$$

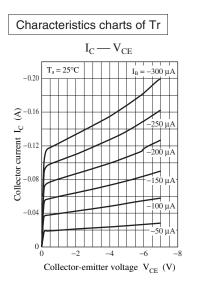
• SBD

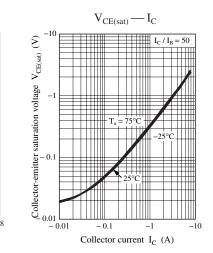
| Parameter             | Symbol          | Conditions   | Min | Тур | Max  | Unit |
|-----------------------|-----------------|--|-----|-----|------|------|
| Forward voltage       | V <sub>F</sub>  | $I_F = 700 \text{ mA}$                               |     |     | 0.45 | V    |
| Reverse current       | I <sub>R</sub>  | $V_R = 20 V$   |     |     | 200  | μΑ   |
| Terminal capacitance  | Ct              | $V_R = 0, f = 1 MHz$                                 |     | 100 |      | pF   |
| Reverse recovery time | t <sub>rr</sub> | $I_F = I_R = 100 \text{ mA}, I_{rr} = 10 \text{ mA}$ |     | 7   |      | ns   |
|                       |                 | $R_L = 100 \Omega$                                   |     |     |      |      |

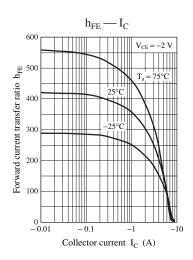
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 Measuring methods for diodes.

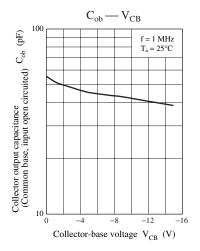
2. Schottky barrier diode is frail with static electricity, and it should be kept in safety from shock of static electricity and static electricity level.

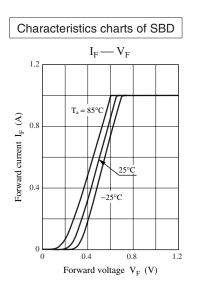


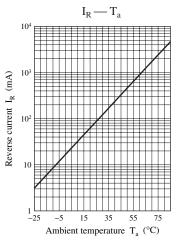


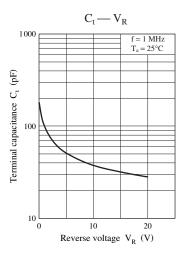












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